

**Amendments to the Claims:**

Please amend claims 1 and 4-6 herein. Please cancel claims 9-18 without prejudice or disclaimer. Please note that all claims currently pending and under consideration in the referenced application are shown below. Please enter these claims as amended. This listing of claims will replace all prior versions and listings of claims in the application.

**Listing of Claims:**

1. (Currently Amended) An intermediate structure of a post-probe tested semiconductor device comprising:  
at least one ~~opened-open~~ open fuse structure on an intermediate structure; and  
a metal feature ~~plated on a first metal structure of the intermediate structure, the metal feature formed after probe testing, wherein the at least one opened fuse structure is not reformed by a metal of the metal feature~~ is present on the first metal structure and is not present on the at least one open fuse structure.
2. (Previously Presented) The intermediate structure of claim 1, wherein the metal feature comprises an electrolessly plated metal feature.
3. (Previously Presented) The intermediate structure of claim 1, wherein the metal feature is a metal layer, an interconnect cap, a redistribution layer, or a bond pad.
4. (Currently Amended) The intermediate structure of ~~claim 3~~ claim 1, wherein the metal feature is ~~the a~~ a metal layer.
5. (Currently Amended) The intermediate structure of claim 1, wherein the metal feature comprises a nickel, palladium, gold, tin, silver, or copper feature.

6. (Currently Amended) The intermediate structure of ~~claim 5~~ claim 1, wherein the metal feature comprises a nickel feature.

7. (Previously Presented) The intermediate structure of claim 1, wherein the first metal structure comprises at least one bond pad.

8. (Previously Presented) The intermediate structure of claim 1, wherein the intermediate structure is an intermediate structure of an SRAM or FLASH memory chip.

Claims 9-18 (Canceled)